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# THIRD SEMESTER M.Sc. DEGREE EXAMINATION, DECEMBER 2015

(CUCSS)

Statistics

# ST 3E 03—STATISTICAL QUALITY CONTROL

(2010 Admission onwards)

Time: Three Hours

Maximum: 36 Weightage

#### Part A

Answer all questions.

Each question carries 1 weightage.

- 1. What are the main causes of quality deviations?
- 2. What is RQL and AQL?
- 3. Define the OC function for a single sampling plan.
- 4. What is a sequential sampling plan?
- 5. Distinguish between defects and defectives.
- 6. Describe a sampling plan for a single specification limit.
- 7. Explain a np chart.
- 8. Describe a p-chart for the fraction of non-conforming units.
- 9. Define ARL of a control chart.
- 10. What is an EWMA chart.
- 11. Define orthogonal arrays.
- 12. What do you understand by process capability studies?

 $(12 \times 1 = 12 \text{ weightage})$ 

## Part B

Answer any **eight** questions. Each question carries 2 weightage.

- 13. Comment on the statement "Quality improvement means reduction of variability in process and products."
- 14. Give the average total inspection under single sampling plan when the sample is not used and the remaining lot is used after defectives are sorted out.
- 15. What is a double sampling plan ? Give the advantages of a double sampling plan over a single sampling plan.

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16. Derive the OC function for a single sampling plan by variables when the standard deviation is known and a single specification limit is given.

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- 17. What do you mean by semi-curtailed and fully curtailed plans? Explain using double sampling plan.
- 18. How is CSP-II and CSP-III plans a modification over the CSP-I plan? Explain.
- 19. Explain the need of constructing a standardized C-chart. Discuss its construction.
- 20. Give the difference between control limits and warming limits. Describe these in the content of control chart for proportion *p*.
- 21. What are probability control limit and three sigma control limit? Illustrate them with reference to an  $\overline{X}$  chart.
- 22. What is a CUSUM chart? Discuss the type of memory it enjoys.
- 23. What is robust quality? What are the main factors that should be considered to achieve Robust quality?
- 24. Define the process-capability index and explain the logic behind this index.

 $(8 \times 2 = 16 \text{ weightage})$ 

### Part C

Answer any **two** questions.

Each question carries 4 weightage.

- 25. Derive the OC function of a sequential sampling plan and comment on it.
- 26. What is the (i) Average cycle length; (ii) Average length of a f 100 % inspection period; (iii) Average outgoing quality of a continuous sampling plan.
- 27. Obtain the control limits on  $\overline{X}$ -R charts when process dispersion is unknown. How do you identify lack of control of the process using  $\overline{X}$ -R charts?
- 28. What is a V mask? How is it used to read a CUSUM chart? Show the equivalence of V mask and tabular CUSUM form.

 $(2 \times 4 = 8 \text{ weightage})$